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| Notice of References Cited | Application/Control No. 10/523,468 | Applicant(s)/Patent Under Reexamination OESTERSCHULZE ET AL. | |
| | Examiner William P. Watkins III | Art Unit 1794 | Page 1 of 1 |

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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